



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Shi-Chang Wooh  
Serial No: 09/898,815  
Filed: July 5, 2001  
For: DEFECT DETECTION SYSTEM  
AND METHOD

Group: 2878  
Examiner: Yam, Stephen K.  
Docket No: MIT-114J

Box Response  
Commissioner for Patents  
Washington, DC 20231

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service as first class mail in an envelope addressed to Box Response, Commissioner for Patents, Washington, DC 20231, on January 18, 2003.

  
Caley Landiorio

RESPONSE

This Response is in reply to the Office Action mailed October 17, 2002 in the subject application. In response to the Office Action, please amend the above-identified application as follows.

AMENDMENT

In the claims:

Please amend claim 4 as follows:

4. (Once amended) The defect detection system of claim 1 in which said detection circuit includes a shear wave sensing circuit for sensing the energy level of the reflected shear waves and the time of arrival of the reflected shear waves at the detection laser system.

Please amend claim 5 as follows:

5. (Once amended) The defect detection system of claim 4 in which said detection

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